What is claimed is:

- 1 1. A material processing apparatus comprising:
- a. a process chamber having a sample holder positioned inside the process chamber 2
- 3 that supports material to be processed;
- b. a plasma chamber comprising a portion of an outer surface of the process 4
- 5 chamber, the plasma chamber containing a gas;
- 6 c. a transformer having a magnetic core surrounding a portion of the plasma
- 7 chamber and a primary winding; and
- 8 d. a solid state AC switching power supply comprising one or more switching
- 9 semiconductor devices coupled to a voltage supply and having an output coupled
- to the primary winding,
 - the solid state AC switching power supply driving an AC current in the primary
- 10 11 11 12 13 winding, the current inducing an AC potential inside the plasma chamber that
 - directly forms a toroidal plasma that completes a secondary circuit of the
- transformer and dissociates the gas, the dissociated gas flowing into the process
 - 15 chamber.
 - 1 2. The apparatus of claim 1 wherein the plasma extends into the process chamber.
 - 1 3. The apparatus of claim 1 wherein the plasma extends to the sample holder.
 - 4. The apparatus of claim 1 wherein a portion of the magnetic core is positioned within 1
 - 2 the process chamber.
 - 1 5. The apparatus of claim 1 wherein the plasma chamber comprises a portion of a top
 - 2 surface of the process chamber.
 - 1 6. The apparatus of claim 1 wherein the plasma chamber comprises a removable lid that
 - 2 is a portion of the process chamber.

- 7. The apparatus of claim 1 wherein the one or more switching semiconductor devices
- 2 comprises one or more switching transistors.
- 1 8. The apparatus of claim 1 wherein the output of the one or more switching
- 2 semiconductor devices is directly coupled to the primary winding.
- 1 9. The apparatus of claim 1 wherein the plasma chamber comprises an electrically
- 2 conductive material and at least one dielectric region that forms an electrical discontinuity
- 3 in the plasma chamber.
- 1 10. The apparatus of claim 9 wherein the electrically conductive material comprises
- 2 aluminum.
- 1 11. The apparatus of claim 10 wherein the aluminum is anodized.
- 1 12. The apparatus of claim 1 wherein the plasma chamber comprises a dielectric material.
- 1 13. The apparatus of claim 1 further comprising an electrode positioned in the plasma
- 2 chamber that generates free charges that assist the ignition of the plasma in the plasma
- 3 chamber.
- 1 14. The apparatus of claim 1 further comprising an electrode capacitively coupled to the
- 2 plasma chamber that generates free charges that assist the ignition of the plasma in the
- 3 plasma chamber.
- 1 15. The apparatus of claim 1 further comprising an ultraviolet light source optically
- 2 coupled to the plasma chamber that generates free charges that assist the ignition of the
- 3 plasma in the plasma chamber.
- 1 16. The apparatus of claim 1 further comprising a circuit for measuring electrical
- 2 parameters associated with the primary winding and the plasma, the electrical parameters
- 3 including one or more of a current driving the primary winding, a voltage across the
- 4 primary winding, an average power in the primary winding, and a peak power in the
- 5 primary winding.

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- 1 17. The apparatus of claim 16 further comprising a power control circuit having an input
- 2 coupled to an output of the circuit for measuring electrical parameters associated with the
- 3 primary winding and the plasma and an output coupled to the solid state AC switching
- 4 power supply, the power control circuit controlling voltage and current supplied to the
- 5 primary winding.
- 1 18. The apparatus of claim 1 further comprising a power supply that is electrically
- 2 coupled to the sample holder, the power supply biasing the material to be processed
- 3 relative to a potential of the plasma.
- 1 19. The apparatus of claim 1 wherein the material to be processed comprises at least one
- 2 of a solid, powder, and a gas.
- 1 20. The apparatus of claim 1 wherein the material to be processed comprises a
- 2 semiconductor material.
- 1 21. A material processing apparatus comprising:
- a. a process chamber;
- b. a plasma chamber comprising a portion of an outer surface of the process
 chamber, the plasma chamber containing a gas;
 - c. a transformer having a magnetic core surrounding a portion of the plasma chamber and a primary winding; and
- d. a solid state AC switching power supply comprising one or more switching semiconductor devices coupled to a voltage supply and having an output coupled to the primary winding,
- the solid state AC switching power supply driving an AC current in the primary
- winding, the current inducing an AC potential inside the plasma chamber that
- directly forms a toroidal plasma that completes a secondary circuit of the

- transformer and dissociates the gas, the dissociated gas flowing into the process chamber, thereby cleaning the process chamber.
- 1 22. The apparatus of claim 21 wherein a portion of the magnetic core is positioned within
- 2 the process chamber.
- 1 23. The apparatus of claim 21 wherein the plasma extends into the process chamber.
- 1 24. The apparatus of claim 21 wherein the plasma chamber comprises an electrically
- 2 conductive material and at least one dielectric region that forms an electrical discontinuity
- 3 in the chamber.
- 1 25. The apparatus of claim 21 further comprising an electrode positioned in the chamber
- 2 that generates free charges that assist the ignition of the plasma in the plasma chamber.
- 1 26. The apparatus of claim 21 further comprising an electrode capacitively coupled to the
- 2 chamber that generates free charges that assist the ignition of the plasma in the plasma
- 3 chamber.
- 1 27. The apparatus of claim 21 further comprising an ultraviolet light source optically
- 2 coupled to the chamber that generates free charges that assist the ignition of the plasma in
- 3 the plasma chamber.
- 1 28. The apparatus of claim 21 further comprising a circuit for measuring electrical
- 2 parameters associated with the primary winding and the plasma, the electrical parameters
- 3 including one or more of a current driving the primary winding, a voltage across the
- 4 primary winding, an average power in the primary winding, and a peak power in the
- 5 primary winding.
- 1 29. The apparatus of claim 28 further comprising a power control circuit having an input
- 2 coupled to an output of the circuit for measuring electrical parameters associated with the
- 3 primary winding and the plasma and an output coupled to the solid state AC switching
- 4 power supply, the power control circuit controlling voltage and current supplied to the
- 5 primary winding.

- 1 30. A method for delivering reactive species to a process chamber, the method
- 2 comprising:
- a. confining a gas in a plasma chamber comprising a portion of the outer surface of
- 4 the process chamber;
- b. generating a current with a solid state AC switching power supply;
- 6 c. inducing an AC potential inside the plasma chamber by passing the current though
- 7 a primary winding of a transformer having a magnetic core surrounding a portion
- 8 of the chamber, the induced AC potential directly forming a toroidal plasma that
- 9 completes a secondary circuit of the transformer and dissociates the gas; and
- d. directing the dissociated gas into the process chamber.
- 1 31. The method of claim 30 further comprising forming a plasma chamber comprising a
- 2 portion of an outer surface of the process chamber.
- 1 32. The method of claim 30 further comprising directing the dissociated gas to material to
- 2 be processed.
- 1 33. The method of claim 30 further comprising extending the plasma into the process
- 2 chamber.
- 1 34. The method of claim 30 further comprising providing an initial ionization event in the
- 2 plasma chamber.
- 1 35. The method of claim 34 wherein the providing of the initial ionization event in the
- 2 chamber comprises applying a voltage pulse to the primary winding.
- 1 36. The method of claim 34 wherein the providing of the initial ionization event in the
- 2 chamber comprises exposing the chamber to ultraviolet light.
- 1 37. The method of claim 30 wherein the gas comprises at least one of a noble gas and a
- 2 reactive gas.

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- 1 38. The method of claim 30 further comprising measuring electrical parameters including
- 2 at least one of the current passing though the primary winding, a voltage across the
- 3 primary winding, an average power in the primary winding, and a peak power in the
- 4 primary winding.
- 1 39. The method of claim 30 further comprising the step of adjusting a magnitude of the
- 2 current generated by the solid state AC switching power supply from the measured
- 3 electrical parameters and from predetermined operating conditions.
- 1 40. The method of claim 30 wherein a pressure in the plasma chamber is substantially
- 2 between 1 mtorr and 100 torr.
- 1 41. The method of claim 30 wherein an electric field of the plasma is substantially
- 2 between 1-100 V/cm.
- 1 42. A method for cleaning a process chamber, the method comprising:
 - a. confining a gas in a plasma chamber comprising a portion of the outer surface of the process chamber;
 - b. generating a current with a solid state AC switching power supply;
 - c. inducing an AC potential inside the plasma chamber by passing the current though a primary winding of a transformer having a magnetic core surrounding a portion of the chamber, the induced AC potential directly forming a toroidal plasma that completes a secondary circuit of the transformer and dissociates the gas; and
- 9 d. directing the dissociated gas into the process chamber, thereby cleaning the process chamber.
- 1 43. The method of claim 42 wherein the reactive gas comprises at least one of an oxygen
- 2 or a fluorine containing gas.
- 1 44. An apparatus for dissociating gases, the apparatus comprising:
- a. a process chamber;

3	b.	a plasma chamber comprising a portion of an outer surface of the process
4		chamber, the plasma chamber comprising an electrically conductive material and
5		at least one dielectric region that forms an electrical discontinuity in the plasma
6		chamber; the plasma chamber containing a gas;

- c. a transformer having a magnetic core surrounding a portion of the plasma chamber and a primary winding; and
- d. a solid state AC switching power supply comprising one or more switching semiconductor devices coupled to a voltage supply and having an output coupled to the primary winding,
 - the solid state AC switching power supply driving an AC current in the primary winding, the current inducing an AC potential inside the chamber that directly forms a toroidal plasma that completes a secondary circuit of the transformer and dissociates the gas, the dissociated gas flowing into the process chamber.
- 45. The apparatus of claim 44 wherein the chamber comprises aluminum.
- 1 46. The apparatus of claim 44 wherein the aluminum is anodized.
- 47. The apparatus of claim 44 wherein the chamber comprises cooling channels for passing a fluid that controls the temperature of the chamber.
- 1 48. A method for delivering reactive species to a process chamber, the method
- 2 comprising:
- a. forming a plasma chamber comprising a portion of an outer surface of a process
 chamber;
- 5 b. confining a gas in the plasma chamber;
- 6 c. generating a current with a solid state AC switching power supply;

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- d. inducing an AC potential inside the plasma chamber by passing the current though
 a primary winding of a transformer having a magnetic core surrounding a portion
 of the chamber, the induced AC potential directly forming a toroidal plasma that
 completes a secondary circuit of the transformer and dissociates the gas; and
 - e. directing the dissociated gas into the process chamber.
 - 49. A method for processing substrates, the method comprising:
- a. forming a plasma chamber comprising a portion of an outer surface of a process
 chamber;
- 4 b. confining a gas in the plasma chamber;
 - c. generating a current with a solid state AC switching power supply;
 - d. inducing an AC potential inside the plasma chamber by passing the current though a primary winding of a transformer having a magnetic core surrounding a portion of the chamber, the induced AC potential directly forming a toroidal plasma that completes a secondary circuit of the transformer and dissociates the gas; and
 - e. directing the dissociated gas onto substrates positioned in the process chamber, thereby processing the substrates.
 - 50. The method of claim 50 wherein the method comprises etching the substrates.
- 1 51. The method of claim 50 wherein the method comprises depositing a dielectric
- 2 material onto the substrates.